# 2SD1280

# Silicon NPN epitaxial planar type

For low-voltage type medium output power amplification

## ■ Features

- Low collector-emitter saturation voltage V<sub>CE(sat)</sub>
- Satisfactory operation performances at high efficiency with the low-voltage power supply.
- Mini power type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing.

# ■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit
Collector-base voltage (Emitter open)	V <sub>CBO</sub>	20	V
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	20	V
Emitter-base voltage (Collector open)	$V_{EBO}$	5	V
Collector current	Ic	1	A
Peak collector current	I <sub>CP</sub>	2	A
Collector power dissipation *	P <sub>C</sub>	1	W
Junction temperature	$T_{j}$	150	°C
Storage temperature	T <sub>stg</sub>	-55 to +150	°C

Note) \*: Printed circuit board: Copper foil area of 1 cm<sup>2</sup> or more, and the board thickness of 1.7 mm for the collector portion

# Unit: mm 4.5±0.1 1.

Marking Symbol: R
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## ■ Electrical Characteristics $T_a = 25$ °C $\pm 3$ °C

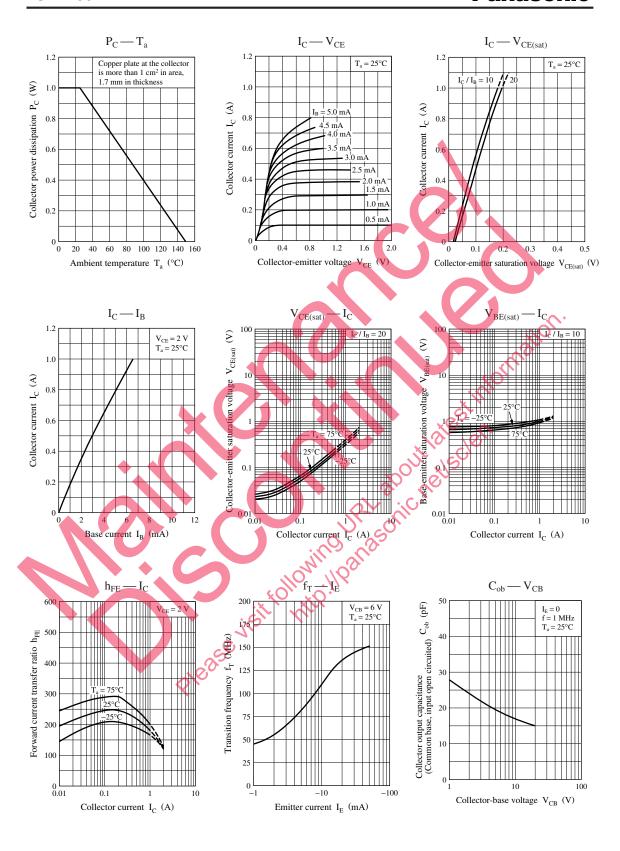
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-emitter voltage (Base open)	V <sub>CEO</sub>	$I_C = 1 \text{ mA}, I_B = 0$	20			V
Emitter-base voltage (Collector open)	$V_{\rm EBO}$	$I_{\rm E} = 10  \mu A, I_{\rm C} = 0$	5			V
Collector-base cutoff current (Emitter open)	I <sub>CBO</sub>	$V_{CB} = 10 \text{ V}, I_E = 0$			1	μΑ
Forward current transfer ratio	h <sub>FE1</sub> *	$V_{CE} = 2 \text{ V}, I_{C} = 0.5 \text{ A}$	90		280	_
	h <sub>FE2</sub>	$V_{CE} = 2 \text{ V}, I_{C} = 1.5 \text{ A}$	50			
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_C = 1 \text{ A}, I_B = 50 \text{ mA}$			0.5	V
Base-emitter saturation voltage	V <sub>BE(sat)</sub>	$I_C = 500 \text{ mA}, I_B = 50 \text{ mA}$			1.2	V
Transition frequency	$f_T$	$V_{CB} = 6 \text{ V}, I_E = -50 \text{ mA}, f = 200 \text{ MHz}$		150		MHz
Collector output capacitance	C <sub>ob</sub>	$V_{CB} = 6 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		18		pF
(Common base, input open circuited)						

Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

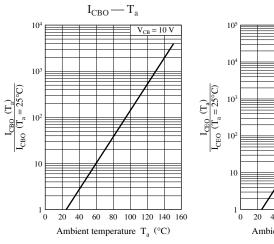
### 2. \*: Rank classification

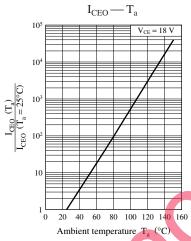
Rank	Q	R	S
h <sub>FE1</sub>	90 to 155	130 to 210	180 to 280

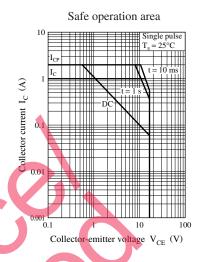
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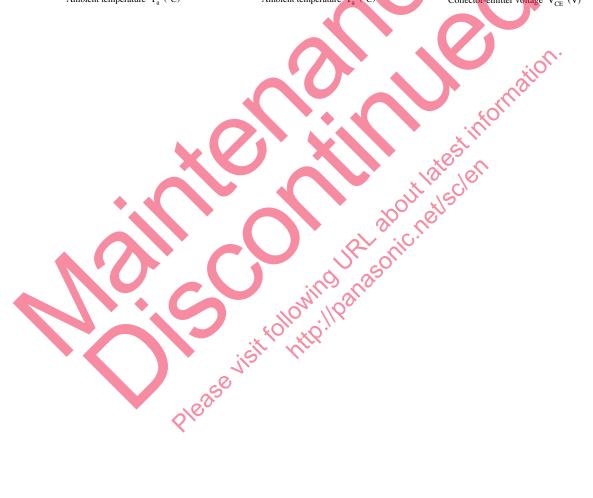


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